

BSE Topography

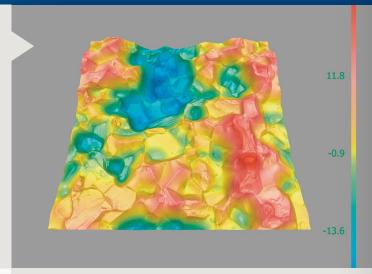
Live and calibrated height measurements, with SEM or FIB-SEM

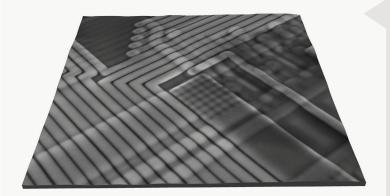


Add the third dimension to your SEM

Measure surface height with SEM

- Use conventional segmented BSE signals
- Measure live with automated topographic reconstruction
- Save topographic data in standard file formats



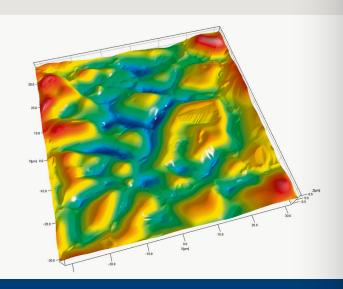


Distinguish topography from composition

- Resolve ambiguities in image interpretation
- Reach a wider audience with 3D models, visualisation and printing
- Measure 3D distances and volumes

Monitor in-situ surface dynamics

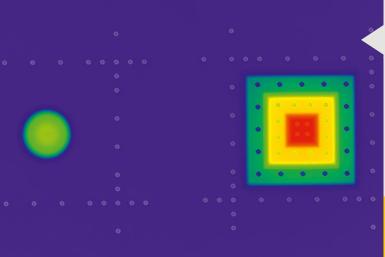
- Record surface evolution during in-situ experiments
- Measure deviations from nominal surface
- Quantify 3D changes for different processes



Visualise complex surfaces in 3D

- Add texture from SE, EDS or EBSD maps
- Apply automatic colour gradients as texture
- Export 3D screenshots for high-impact visualisation





Calibrate and measure heights

- Calibrate measurements with dedicated 3D samples
- Measure 3D positions, distances and angles
- Measure and report height profiles

BSE Topography

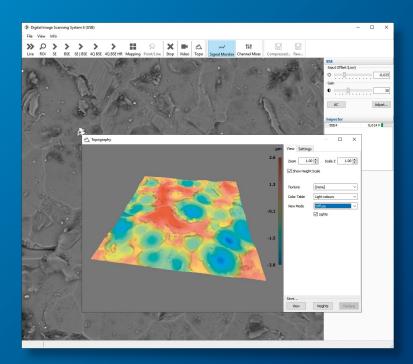
Continue live topography with off-line analysis

- Import data into full feature analysis software
- Measure surface roughness and analyse texture
- Analyse morphology, grain and particle distribution





Live calibrated height measurements with any SEM or FIB-SEM

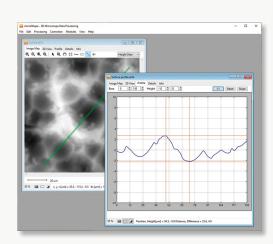


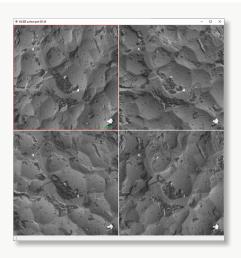
DISS6 - detector control and image acquisition app

- Live surface height reconstruction from BSE signals
- Built-in 3D surface visualisation tool
- Configurable workflows with integrated SE and BSE scan profiles

microShape - surface topography app

- Load, view and edit height and texture layers
- View and manipulate data in 3D
- Extract and export 3D line profiles
- Export standard PLY files for 3D printing





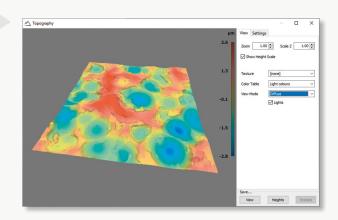
Quantitative 4Q BSE acqusition

- Factory calibrated amplification and digitisation
- Automatic offset and gain corrections
- Live inspection of calibrated pixel values

BSE Topography

Live topographic reconstruction

- Pan, rotate, tilt, zoom and scale height
- Enhance views with shadows and pseudo-colour
- Texture with BSE average or surface gradients

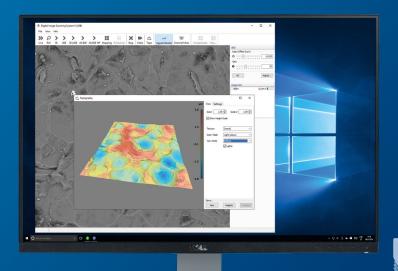


Automated 3D calibration

- Use 3D reference sample to calibrate acquisition
- Get automatic scale parameters for x, y and z
- Save scale parameters for different SEM configurations



Turn-key solution for any SEM or FIB-SEM



Quantitative electronics for BSE acquisition

- 3D calibration sample
- BSE detector
- Scan generator
- Data acquisition

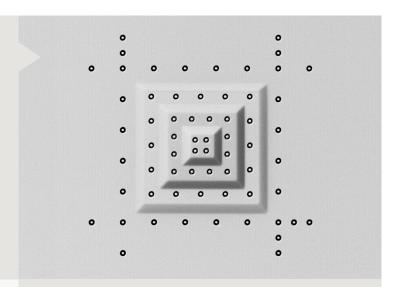






3D calibration sample

- FIB-SEM deposited 3D structures with reference marks for automated calibration
- Calibrated 3D reference data acquired with a metrological SPM system
- Automated, statistical 3D calibration algorithm





BSE detector

- Segmented 4Q Si sensors for topography
- In situ preamplifiers for minimum noise and maximum speed
- Automated insertion/retraction on port mount

BSE Topography

BSE DISS6 imaging

- Signal amplifier, scan generator and image acquisition
- Simultaneous acquisition of all signals
- Advanced offset and gain normalization
- Very large image resolution





3D calibration sample

| Calibration structures | 3× multi-level pyramidal elements |
|---------------------------|---|
| | 1× spherical element |
| | reference marks |
| Pyramidal elements | produced by GIS deposition |
| | $3\times$ with nominal size of $20\times20\times3~\mu m$ |
| | $3\times$ with nominal size of $10\times10\times1,8~\mu m$ (optional) |
| Spherical element | produced by GIS deposition |
| | 10 × 10 × 1 μm |
| Auto-recognition elements | produced by FIB milling |
| | 800 nm diameter |
| | 600 nm diameter (nominal) |
| Total area | 80 × 80 μm |
| | 40 × 40 μm (optional) |
| Reference data | Binary file on USB-drive |
| | |

BSE detector

| Sensor | detector-grade Si chip |
|---------------|--|
| | four-quadrant (4Q) geometry |
| | chip on ceramic board mount |
| | 6 mm inner diameter |
| | 20 mm outer diameter |
| | 1 kV minimum acceleration voltage |
| Pre-amplifier | in situ mount |
| | 10⁵ V/A gain |
| | 200 ns minimum dwell time (gain dependent) |
| Mechanics | port mounted, motorised insertion/retraction |
| | adjustable height and lateral alignment |
| | automatic touch alarm |
| | integrated electrical feedtroug |

BSE DISS6 imaging

| Signal inputs | BSE 14 |
|-------------------------------|--|
| | AUX 14 |
| BSE 14 amplification | -11 V input offset (calibrated brightness 14) |
| | 11,800× gain (calibrated contrast 14) |
| | -0.5 0.5 V output offsets (calibrated reference 14 |
| | BSE average (hardware mix of 14) |
| | 3.4 MHz 34 Hz low-pass filter |
| 4Q BSE control | automated 4Q global brightness |
| | automated 4Q global contrast |
| | automated input offsets (dark correction) |
| | automated gain normalisation (bright correction) |
| | automated time filter (matching pixel dwell time) |
| Digitization | 12-bit (calibrated BSE14) |
| | 8× simultaneous signals (BSE14 and AUX14) |
| | 32,000× max. oversampling (pixel averaging) |
| Scan generator | X and Y scan outputs (calibrated) |
| | beam blank output (optional) |
| | 64k × 64k pixels maximum resolution |
| | 0.5 GPixels maximum frame size (software limit) |
| | 200 ns minimum pixel dwell time (detector limited) |
| | 6 milliseconds maximum pixel dwell time |
| | 256× max. frame average |
| | 50x max. line average |
| | frame, line, pixel synchronization (optional) |
| PC/Laptop, display (optional) | |
| PC/Laptop | Intel Core i3 minimum |
| | 2× USB 2.0 minimum |
| | Windows 117 |
| | Network is recommended for remote support |

Display 1,280 × 1,024 resolution minimum



DISS6 app

| Detector control | automatic insertion/retraction |
|------------------|--|
| | contrast and brightness |
| | input offset and gain normalisation corrections |
| | live calibrated pixel values |
| | live grayscale 'topographic' and 'compositional' mix |
| Topography tool | live topographic calculation from BSE14 |
| | live 3D view of height and texture |
| | rotation, shift, zoom and scale controls |
| | colour look-up-tables |
| | automatic spherical correction |
| | automatic X, Y and Z scale corrections |
| File formats | compressed 8-bit multi-page TIF with XMP tags |
| | raw 16-bit multi-page TIF with XMP tags |
| | binary AL3D |
| | plain text SDF |
| Operating system | Windows 117 |
| | |

microShape app

| The same of the sa | |
|--|--------------------------------------|
| Topography viewer | AL3D file format |
| | ASCII, 8/16-bit TIFF file formats |
| | BCR, Surfer DAT export formats |
| | 2D view of texture and height layers |
| | 3D view of complete topographic data |
| Topography processing | crop, rotate, resize |
| | scale and shear 3D corrections |
| | geometric scan corrections |
| | texture layer replacement |
| 4Q BSE reconstruction tool | common SEM image file formats input |
| | configurable detector geometry |
| | shape-from-shading algorithm |
| 3D measurements tools | 3D points, distances and angles |
| | spherical and polynomial surface fit |
| | 3D height line profile graphs |
| | PDF report file format |
| | ASCII, CSV data export file formats |
| 3D print | PLY export file format |
| Operating system | Windows 117 |
| | |

Parts and cables

| 3D calibration sample | standard 1× |
|-----------------------|-------------|
| BSE detector | standard 1× |
| BSE DISS6 imaging | standard 1× |
| SEM scan cable | standard 1× |
| BSE detector cable | standard 1× |
| Mains power cable | standard 2× |
| USB cable | standard 2× |
| USB flash drive | standard 1× |
| PC, keyboard, mouse | optional 1× |
| Displays | optional 1× |
| | |

Software packages

| Drivers | PE USB driver |
|-----------|---------------------|
| Libraries | DISS6Control |
| | DISS6Topography |
| Software | DISS6 app |
| | microShape app |
| | EM Gateway server |
| | microCal (optional) |
| | |

Weight and dimensions

| Shipping | typ. 36 × 32 × 150 cm |
|----------|-----------------------|
| | typ. 12.5 kg |

Site requirements

| Power | 2x mains 110/220 VAC single phase 50/60 Hz |
|---------|---|
| | on the same earth as the microscope |
| Mount | 1× flange for BSE detector |
| lmaging | 1× external scan interface on the SEM electronics |
| Space | BSE DISS6 unit may be placed on the SEM table |





SALES & SERVICE

sales@pointelectronic.de +49 345 1201190

SUPPORT & TRAINING

support@pointelectronic.de +49 345 1201190

CUSTOM ENGINEERING

engineering@pointelectronic.de +49 345 47225619

point electronic GmbH | Erich-Neuß-Weg 15 | 06120 Halle (Saale) | Germany Tel.: +49 345 1201190 | Fax: +49 345 1201223 | info@pointelectronic.de | www.pointelectronic.de

